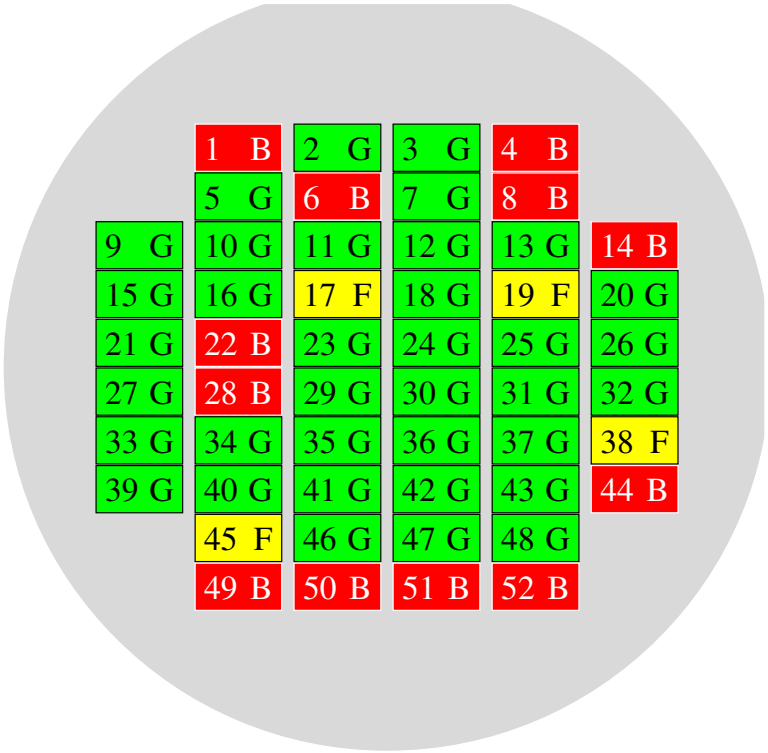
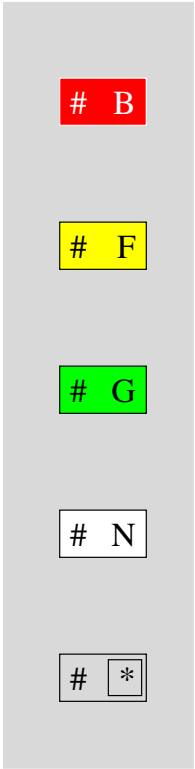
Die quality map for wafer 34 s/n: 21316-03-02

Date: 11/01/98





Bad die

Fair die

Good die

No info

Manually tagged